

Amendment to the Claims

Please cancel claim 4, and amend claims 1 and 11 as shown in the following listing of claims. This listing of claims will replace all prior versions, and listings, of claims in the application.

1. (currently amended) A method of testing analogue or radio frequency circuitry for the presence of faults, the method comprising the steps of:

a) ramping up a power supply being supplied to a circuit or component under test to apply ~~applying~~ a plurality of different DC power supply voltages to ~~[[a]]~~ the circuit or component under test, at least one of said power supply voltages being arranged to cause at least some of the elements of the circuit or component under test to operate in a predetermined region of operation; and

b) measuring the quiescent current of said circuit or component after application of each of said power supply voltages to generate a current signature representative of the operation of said circuit or component;

the method being characterized in that said power supply voltages at which said quiescent current measurements are taken comprise selected distinct voltages; and by the step of:

c) comparing said generated current signature with a predetermined current signature representative of operation of a fault-free component or circuit so as to determine whether or not any faults are present in the component or circuit under test.

2. (original) A method according to claim 1, including the further step of measuring one or more selected nodal voltages, in addition to said quiescent current, as a result of application of said selected power supply voltages.

3. (original) A method according to claim 2, wherein said one or more nodal voltages are measured at one or more respective output nodes of said circuitry.

4. (canceled).

1 5. (previously presented) A method according to claim 1, wherein the
2 selected power supply voltages are selected so as to cause at least some of the
3 elements of the circuitry under test to pass through several regions of operation.

1 6. (previously presented) A method according to claim 1, wherein a fault
2 dictionary database is provided, and the method includes the further step of
3 comparing a generated current signature with contents of such a database to
4 diagnose one or more faults present in the circuitry under test.

1 7. (previously presented) A method according to claim 1, wherein a
2 tolerance window is defined for the resultant quiescent current measurements for
3 at least one of the selected power supply voltages.

1 8. (original) A method according to claim 7, wherein a tolerance window is
2 defined for the resultant quiescent current measurements for all of the selected
3 power supply voltages.

1 9. (previously presented) A record carrier on which is stored a computer
2 program for enabling the method of claim 1 to be performed.

1 10. (previously presented) A method of testing analogue or radio frequency
2 circuitry, including the step of making available for downloading a computer
3 program for enabling the method of claim 1 to be performed.

1 11. (currently amended) Apparatus for testing analogue or radio frequency
2 circuitry for the presence of faults, the apparatus comprising:
3 a) means for ramping up a power supply being supplied to a circuit
4 or component under test to apply ~~applying~~ a plurality of different DC power
5 supply voltages to ~~[[a]]~~ the circuit or component under test, at least one of said
6 power supply voltages being arranged to cause at least some of the elements of the
7 circuit or component under test to operate in a predetermined region of operation;
8 and

9 b) means for measuring the quiescent current of said circuit or
10 component after application of each of said power supply voltages to generate a
11 current signature representative of the operation of said circuit or component;
12 the apparatus being characterized in that said power supply
13 voltages comprise selected distinct voltages; and by:
14 c) means for comparing said generated current signature with a
15 predetermined current signature representative of operation of a fault-free
16 component or circuit so as to determine whether or not any faults are present in
17 the component or circuit under test.

1 12. (previously amended) A method according to claim 1, wherein the
2 different DC power supply voltages are selected to cause at least some of the
3 elements of the circuit or component under test to pass through subthreshold,
4 linear and saturation operating regions.